

<b>APPLICATION ART CITATION</b> (Use several sheets if necessary) <div style="border: 1px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 0 auto;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">             RECEIVED              APR 12 2004              PATENT &amp; TRADEMARK OFFICE           </div> </div>		Application <b>10/692,152</b>		OFGS File No. <b>P/2041-68</b>			
		Applicant <b>Hiroyuki UNO et al</b>					
		Filing Date <b>October 22, 2003</b>		Group Art Unit <b>2642</b>			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
WK	US-2002/0070923 A1	06-2002	Levy, et al				
	US-						
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<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
WK	EP 0 872 996 A2	10-1998	EP			X	
WK	EP 1 128 642 A2	08-2001	EP			X	
WK	WO 01/45359 A1	06-2001	PCT			X	
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
WK		European Search Report dated March 4, 2004 issued in connection with corresponding					
WK		European application no. 03 023 528.7					
Examiner <i>W. Ray Kim</i>		Date Considered <i>7/12/05</i>					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							